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Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/683,570	OGUSHI ET AL.	
Examiner	Art Unit	
Kidost Bohta	2425	

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED				
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705	16	107	q	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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